

iFlaw-80 Ultrasonic Flaw Detector



Product Features and Application

Product Features

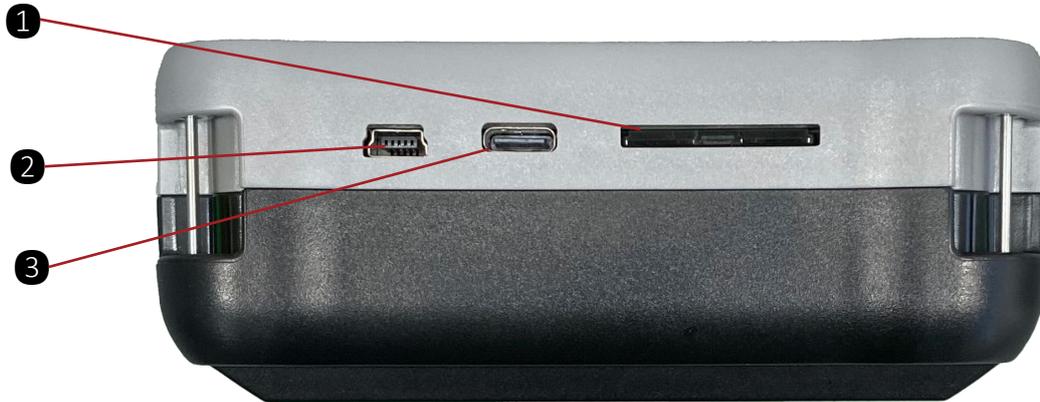
- The body is lightweight and suitable for one-handed operation.
- PD65W fast charge + 12 hours long battery life.
- 5.0-inch IPS high-definition display with a brand new UI interface.
- Support full-screen touch, quick gesture operation, virtual keyboard, easy to use
- With DAC, AVG, automatic gain, peak memory, color half-span, B-scan and other professional functions.
- Including Chinese and English switching, data export to SD card, online upgrade, screen capture and many other practical functions.

Product Application

- Mechanical manufacturing: Testing mechanical equipment components and large castings and forgings
- Petrochemical industry: Used for equipment such as pipelines and pressure vessels
- Aerospace: Flaw detection for key components of aircraft and spacecraft
- Steel structure inspection: Inspect welds, bolt connections, and other parts
- Concrete structure inspection: Exploring defects such as cracks and voids
- Track inspection: Flaw detection of steel rails
- Vehicle detection: Detecting key components of trains, subways, and other vehicles
- Special equipment testing: Flaw detection for boilers, elevators, etc
- Cultural relic preservation: To inspect the internal structure of cultural relics, providing solutions for restoration without damaging their appearance.



Instrument Interface



1.SD card slot

2.Mini USB data interface

3. Charging interface/Type-C data interface



1.Power switch **2.B-scan trolley encoder interface**
4.Transmitting interface

3.Receiving interface

Button Function



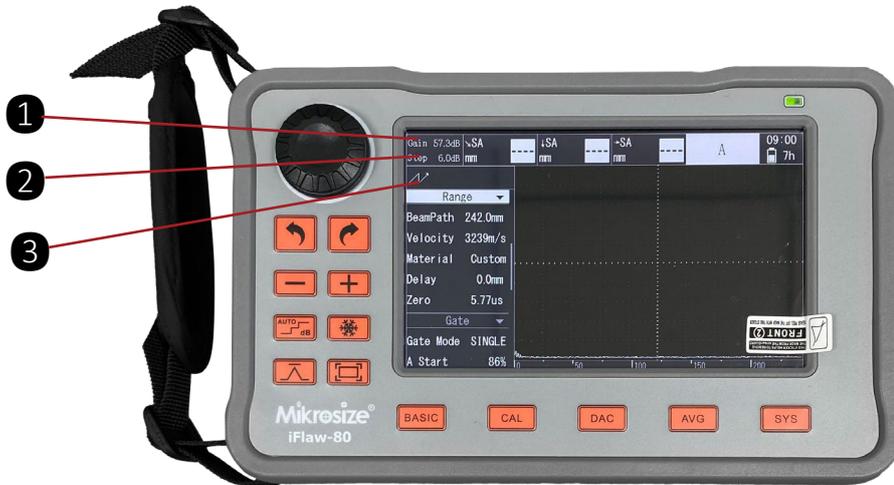
**1.Shuttle key 2.Function keys/Shortcut keys 4.Status indicator light 3.Menu key
(Green light: Normal operation, Red light: Charging)**

Button Function



- 1. Long press for recording function / Short press for freeze function (to hold the displayed waveform on the screen)**
- 2. Automatic peak button (default at 80%)**
- 3. Long press for screenshot function / Short press for full-screen waveform display function**
- 4. Long press for gate expansion function / Short press for peak memory function**
- 5. Shortcut key for basic menu**
- 6. Calibration menu: Sound velocity + Zero point, shortcut key for angle calibration menu of angle beam probe**
- 7. DAC curve menu key**
- 8. AVG curve menu key**
- 9. Shortcut key for system settings menu**

Interface Display



1.Current Total Gain Value

2.Current Gain Step

3.Status Display



Parameter Menu
13.Current Time and Battery Level Display

2.Measurement Value Display

Curve Display

DAC Curve

- The DAC curve includes RL (rejection line), SL (quantification line), and EL (evaluation line)
- High quantitative accuracy;
- Adjustable detection sensitivity;
- More precise defect localization;
- The comparability of the results is strong;
- Convenient quality control

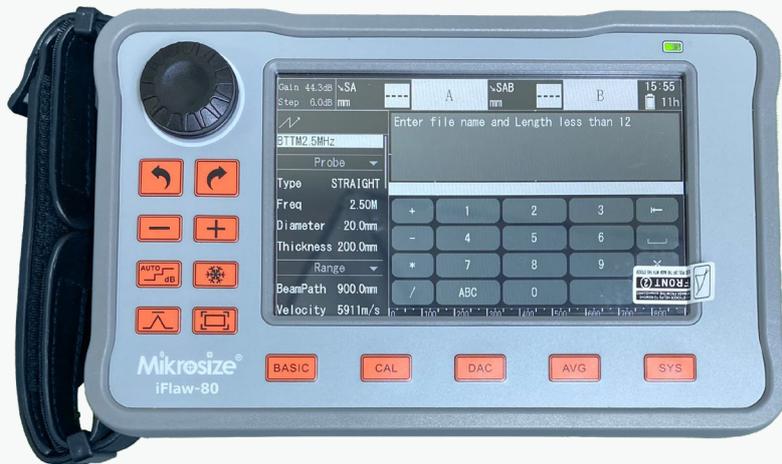


AVG Curve

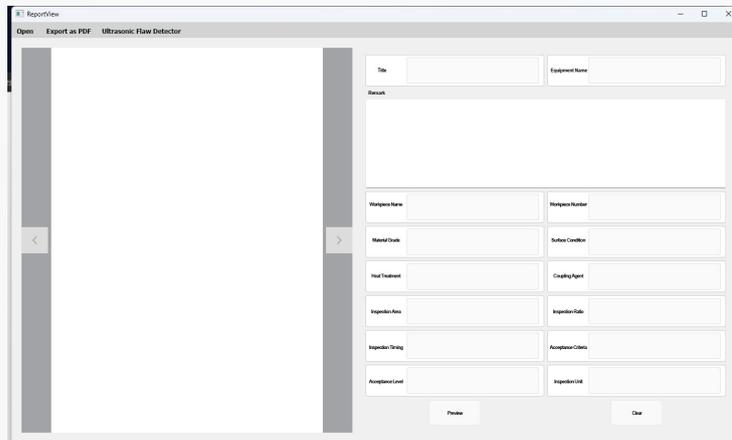
- AVG curve only supports the use of straight probes
- Accurate quantification of defects
- High detection sensitivity
- Defect localization assistance
- Good reproducibility of results
- Widely applicable
- The AVG curve can provide distance information between the defect and the probe. By measuring the arrival time of the defect echo and combining it with the known sound velocity, the position of the defect can be calculated



Data Storage

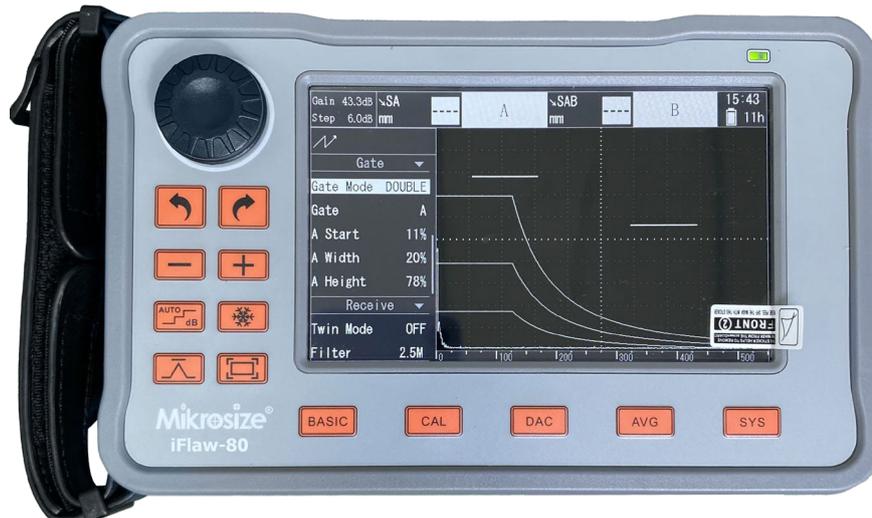


After recording and taking a screenshot, you can set the file name and preview the content. It is possible to generate an inspection report and transfer it to computer software, where you can set parameters in the inspection report (such as testing unit, workpiece name, workpiece number, etc.).



Set the USB flash drive mode on the instrument; connect it to the computer via the Type-C data cable interface, and you can use the software to edit the content of the inspection report results. PDF files can be generated.

Gate Setting



Single or double gates can be set in the basic menu.

Double gates can enhance the accuracy and flexibility of detection, improve detection efficiency, and facilitate data analysis and recording.

Double gates can be flexibly set according to different inspection standards and workpiece characteristics. By adjusting the width, height, and position of the gates, they can adapt to defect detection of different sizes and shapes.

Double gates can simultaneously monitor multiple areas, enabling quick location of potential defects. This allows flaw detection personnel to complete inspections of workpieces in a shorter period, thereby improving inspection efficiency.

Technical Parameters

| | |
|---------------------------------|--|
| Bandwidth | 0.1MHz~20MHz |
| Gain | 120dB,pace 0.1dB,0.6dB,1dB,2dB,6dB |
| Wave filter | Broadband,1M,1.25M,2.5M,5M,10M,15M,1M-5M |
| Sampling rate | Hardware sampling rate 100MSPS,equivalent sampling rate 400MSPS |
| Detection mode | Full wave, positive half wave, negative half wave, RF, envelope |
| Detection range | 10 meters (longitudinal wave carbon steel),pace 100mm、 10mm 、 0. 1mm |
| Pulse mode | Sharp pulse, square wave, dual-square wave |
| Pulse voltage | 25V~300V , 25V pace |
| Pulse width | 0ns~500ns continuously adjustable,5ns pace |
| Emission damping | Strong(100Ω),weak(1000Ω)adjustable |
| Pulse frequency | Automatic or manual, automatic range(200Hz-1KHz),manual range(0-10KHz) |
| Probe channel | 200 groups, supporting operations such as creating, previewing, deleting, renaming, overwriting, and restoring |
| Gate alarm | Gate A and B alarm, lost wave/incoming wave |
| Gate mode | Independent gate A, gate B |
| Measurement mode | Peak, Front edge, J Front edge |
| Quantitative mode | DAC curve ,AVG(DGS) curve |
| Flaw detection standards | AWS D1.1/D1.5,NB/T 47013,GB/T 29712,GB/T 11345 |
| Saving content | Single frame, multi-frame recording (≤ 500 frames), screenshot,flaw detection report |
| Auxiliary functions | Automatic gain, peak memory, waveform freezing, channel management, gate alarm, gate expansion, automatic gate, full screen touch, virtual keyboard, color half span, quick screenshot |
| Display screen | High definition 5.0 inch 800×480 IPS_LCD |
| Probe interface | Dual LEMO-00 C5 |
| Output interface | Type-C,MINI USB |
| Data storage | 8GB SD card |
| Charger | PD fast charging ,standard Type-C interface(100~240V,50~60Hz) |
| Size | 183mm×113mm×45mm |
| Weight | 700g,including battery but not rubber sleeve |
| Language | Chinese, English |
| Unit | Metric system ,Imperial system |
| Battery | 7.4V 8000mAh Lithium battery, 12 hours of battery life |
| Operation temperature | -10°C~55°C |
| Resolution ratio | 40dB(Metrological performance requirements: ≥26dB) |
| Dynamic range | 32dB(Metrological performance requirements: ≥26dB) |
| Sensitivity margin | 50dB(Metrological performance requirements: ≥42dB) |
| Vertical linearity | 1.8%(Metrological performance requirements: ≤6%) |
| Horizontal linearity | 0.5%(Metrological performance requirements: ≤2%) |

Standard Delivery

| Items | Qty | |
|--|-----|--|
| Host | 1 | |
| Probe (high-precision straight probe, angle probe) | 1 |  |
| Probe line | 1 |  |
| Charger | 1 |  |
| Power line | 1 |  |
| User manual | 1 | |
| Certificate | 1 | |
| Warranty card | 1 | |
| SD card(8G) | 1 | |
| Conversion plug (USB to C) | 1 |  |

Optional Delivery

| Items | Qty | |
|------------------------|-----|--|
| SD card(16G, 32G, 64G) | 1 |  A SanDisk Ultra 8GB SD card is shown. The card is black with a white label. The label features the SanDisk logo at the top, followed by 'Ultra' in a stylized font. Below that, it says '40 MB/s' and 'UHS-I'. The capacity '8 GB' is prominently displayed in red. At the bottom of the label, the SanDisk logo is repeated in a red box. |
| Power bank | 1 | |